



ÆÑE UNITED STATES PATENT AND TRADEMARK OFFICE

In the Application of: Getty et al. 7087

CASE NO.: CL2127 US NA

APPLICATION NO.: 10/817,088

GROUP ART UNIT: UNKNOWN

FILED: APRIL 2, 2004

EXAMINER: UNKNOWN

FOR: SCREENING FOR ELECTRICAL CONDUCTIVITY OF MOLECULES BY

MEASURING SURFACE POTENTIAL

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents Washington, D.C. 20231

Sir:

In compliance with 37 CFR 1.97 and 1.98, Applicants bring to the attention of the U.S. Patent and Trademark Office information listed on the enclosed PTO/SB/08A and PTO/SB/08B. A copy of the information is also enclosed.

Should any fee be required in connection with the filing of this Information Disclosure Statement, please charge such fee to Deposit Account No. 04-1928 (E. I. du Pont de Nemours and Company).

Respectfully submitted,

S. NEIL FELTHAM

Attorney for Applicant(s)

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Dated: 7/30/04

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MARY BETH PITCHER

10-817089



PTO/SB/08A (08-00)

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				Application Number	10/817,088 / 10-817089		
INFC	RMATION	DIS	CLOSURE	Filing Date	April 2, 2004		
STA	TEMENT B	YA	PPLICANT	First Named Inventor	Getty et al.		
				Group Art Unit	Unknown		
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Sheet	1	of	2	Attorney Docket Number	CL2127 US NA		

					U.S. PATENT DOCU	MENTS /	
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Examiner Initials *	Cite No.	Number	Number Kind Code ² (if known)		of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevan Passages or Relevant Figures Appear
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10-817089

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				Group Art Unit	Unknown	
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		OTHER PRIOR ART - NON PATENT LITERATURE DECUMENTS	
Examiner Initials *	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
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